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Michael Navarro

PATENT
ESD1.PAU.02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Rodov et al.

Serial No.: 10/635,390

Filed: August 6, 2003

Title: Method and Apparatus for
Preventing Microcircuit
Dynamic Thermo-Mechanical
Damage During and ESD
Event

Art Unit: 2818

Examiner: Mai Huong C. Tran

INFORMATION DISCLOSURE STATEMENT

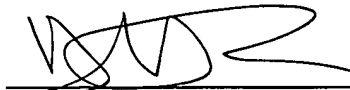
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Sir:

In accordance with 37 C.F.R. § 1.56, Applicant(s) submit herewith the attached Information Disclosure Statement Form PTO-1449 in connection with the above-identified patent application. The statement is not a representation that all of the information cited is necessarily effective as prior art against the application. Also, Applicant has co-pending application serial no. 10/635,391 filed August 6, 2003 which may be considered to be directed to related subject matter. If any fee is required for consideration of this Information Disclosure Statement please charge Deposit Account No. 01-1960.

Respectfully submitted,

Date: 6/11/04


David L. Henty
Attorney for Applicant(s)
Reg. No. 31,323

MYERS, DAWES ANDRAS & SHERMAN, LLP
19900 MacArthur Blvd., Suite 1150
Irvine, CA 92612
Telephone: (949) 223-9600
Facsimile: (949) 223-9610

FORM PTO-1449 (MODIFIED) MADE BY:	ATTY. DOCKET NO. ESD1.PAU.02	SERIAL NO. : 10/635,390
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANT(S): Rodov et al.	
	FILING DATE: August 6, 2003	GROUP: 2818

Reference Designation

U.S. PATENTS

Examiner Initial	Document Number	Date	Name	Class	Filing Date Subclass if appropriate
	6,153,913	11/28/2000	Hsu et al.		
	5,537,284	07/16/1996	Haas, Jr. et al.		
	6,157,530	12/05/2000	Pequignot et al.		
	6,268,286	07/31/2001	Gauthier, Jr. et al.		
	6,034,388	03/07/2000	Brown et al.		
	6,331,726	12/18/2001	Voldman		
	5,689,133	11/18/1997	Li et al.		
	6,292,343	09/18/2001	Pequignot et al.		
	6,262,873	07/17/2001	Pequignot et al.		
		FOREIGN PATENT DOCUMENTS			
	Document Number	Date	Country	Class	Filing Date Subclass if appropriate
OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)					
	Test Structures for Benchmarking the Electrostatic Discharge (ESD) Robustness of CMOS Technologies, Sematech, Inc., February 27, 1998				
	Characterization, Modeling, and Design of ESD Protection Circuits, Stephen G. Beebe, Advanced Micro Devices, March 1998				
	Investigation of ESD Performance in Advanced CMOS Technology, A dissertation Submitted to the Department of Electrical Engineering and the Committee on Graduate Studies of Stanford University in Partial Fulfillment of the Requirements for the Degree of Doctor of Philosophy, Kwang-Hoon Oh, October 2002				
	Lighting Rods for Nanoelectronics, Steven H. Voldman, <i>Scientific American</i> , Vol. 287, No. 4, Pgs. 90-97, October 2002				
EXAMINER			DATE CONSIDERED		